

**Implementation-independent test generation for a large class of faults in RISC processor modules**  
**Jenihhin, Maksim; Oyeniran, Adeboye Stephen; Raik, Jaan; Ubar, Raimund-Johannes** 24th Euromicro Conference on Digital System Design (DSD) 2021 <https://doi.org/10.1109/DSD53832.2021.00090>

**Network-on-ReRAM for scalable processing-in-memory architecture design**  
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